

	Hits	Search Text	DBs	Time Stamp
43	0	S42 and S24	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2004/07/06 10:35
44	45	S42 and parametric	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2004/07/06 10:40
45	0	(creat\$6 or form or forming or fabricat\$6) near4 (gate adj insulat\$6) near8 (used or using or use) near8 (predetermined near2 (test or testing or result or value or parameter or parametric))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2004/07/06 10:41
46	21	(creat\$6 or form or forming or fabricat\$6) same (gate adj insulat\$6) same (used or using or use) same (predetermined near2 (test or testing or result or value or parameter or parametric))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2004/07/06 11:38
47	206	(test or testing or check or checking) near8 (gate near2 insulat\$6)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2004/07/06 11:39
48	24357	insitu or in adj situ	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/04 10:38

	Hits	Search Text	DBs	Time Stamp
49	18647	(test or testing) near7 (gate adj insulator or gate insulation)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/04 10:42
50	62	S48 and S54	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/04 10:42
51	1674	(438/14).CCLS.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/04 10:42
52	13	gate adj insulator and S56	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/04 10:43
53	0	("2003/0199145").UR PN.	USPAT	2005/01/04 10:43
54	5	("4957877" "4960675" "5663076" "5822241" "5943550").PN.	US-PGPUB; USPAT; USOCR	2005/01/04 10:44
55	2	("6228663").PN.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/04 10:44
56	5	("4957877" "4960675" "5663076" "5822241" "5943550").PN.	US-PGPUB; USPAT; USOCR	2005/01/04 10:44
57	3	("6228663").URPN.	USPAT	2005/01/04 10:45
58	2	("5793675").PN.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2005/01/04 10:47